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"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Not For New Designs
Core Processor	STM8
Core Size	8-Bit
Speed	16MHz
Connectivity	I²C, IrDA, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, DMA, LCD, POR, PWM, WDT
Number of I/O	68
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	2K x 8
RAM Size	4K x 8
Voltage - Supply (Vcc/Vdd)	1.65V ~ 3.6V
Data Converters	A/D 28x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	80-LQFP
Supplier Device Package	80-LQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm8al3l8atcy

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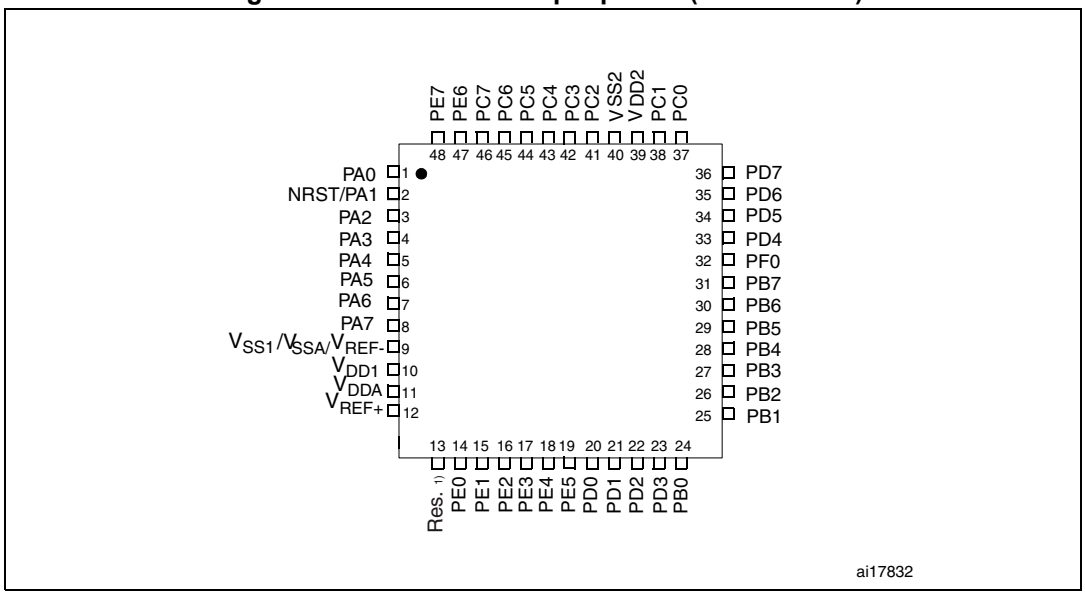
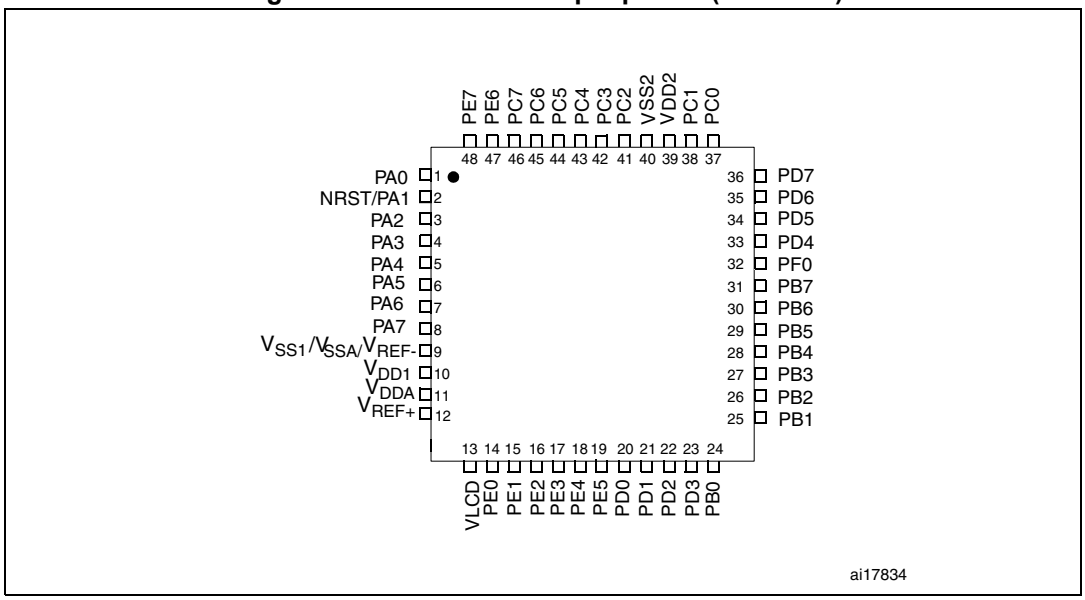
Figure 7. STM8AL3188 48-pin pinout (without LCD)



1. Pin 13 is reserved and must be tied to V_{DD}.
2. The above figure shows the package top view.

Figure 8. STM8AL3L88 48-pin pinout (with LCD)



1. The above figure shows the package top view.

Table 5. High-density STM8AL3x8x pin description (continued)

Pin number			Pin name	Type	I/O level	Input			Output			Main function (after reset)	Default alternate function
LQFP80	LQFP64	LQFP48				floating	wpu	Ext. interrupt	High sink/source	OD	PP		
45	37	-	PB6/SPI1_MOSI/ LCD_SEG16(3)/ ADC1_IN12/COMP1_INP	I/O	FT(5)	**X**	X	X	HS	X	X	**Port B6**	SPI1 master out/slave in/ LCD segment 16 / ADC1_IN12/Comparator 1 positive input
-	-	30	PB6/SPI1_MOSI/ LCD_SEG16(3)/ ADC1_IN12/DAC_OUT2/ COMP1_INP	I/O	FT(5)	**X**	X	X	HS	X	X	**Port B6**	SPI1 master out/ slave in / LCD segment 16 / ADC1_IN12 / DAC channel 2 output/Comparator 1 positive input
46	38	31	PB7/SPI1_MISO/ LCD_SEG17(3)/ ADC1_IN11/COMP1_INP	I/O	FT(5)	**X**	X	X	HS	X	X	**Port B7**	SPI1 master in- slave out/ LCD segment 17 / ADC1_IN11/Comparator 1 positive input
65	53	37	PC0/I2C1_SDA	I/O	FT(5)	**X**		X		T(6)	-	**Port C0**	I2C1 data
66	54	38	PC1/I2C1_SCL	I/O	FT(5)	**X**		X		T(6)	-	**Port C1**	I2C1 clock
69	57	41	PC2/USART1_RX/ LCD_SEG22/ADC1_IN6/ COMP1_INP/VREFINT	I/O	FT(5)	**X**	X	X	HS	X	X	**Port C2**	USART1 receive / LCD segment 22 / ADC1_IN6/Comparator 1 positive input/Internal reference voltage output
-	-	42	PC3/USART1_TX/ LCD_SEG23(3)/ ADC1_IN5	I/O	FT(5)	**X**	X	X	HS	X	X	**Port C3**	USART1 transmit / LCD segment 23 / ADC1_IN5
70	58	-	PC3/USART1_TX/ LCD_SEG23(3)/ ADC1_IN5/COMP2_INM/ COMP1_INP	I/O	FT(5)	**X**	X	X	HS	X	X	**Port C3**	USART1 transmit / LCD segment 23 / ADC1_IN5 / Comparator 2 negative input /Comparator 1 input positive
71	59	43	PC4/USART1_CK/ I2C1_SMB/CCO/ LCD_SEG24(3)/ ADC1_IN4/COMP2_INM/ COMP1_INP	I/O	FT(5)	**X**	X	X	HS	X	X	**Port C4**	USART1 synchronous clock / I2C1_SMB / Configurable clock output / LCD segment 24 / ADC1_IN4 / Comparator 2 negative input / Comparator 1 positive input
72	60	44	PC5/OSC32_IN /*[SPI1_NSS]*(2)/ *[USART1_TX]*(2)	I/O	FT(5)	**X**	X	X	HS	X	X	**Port C5**	LSE oscillator input / *[SPI1 master/slave select] / [USART1 transmit]*

Table 5. High-density STM8AL3x8x pin description (continued)

Pin number			Pin name	Type	I/O level	Input			Output			Main function (after reset)	Default alternate function
LQFP80	LQFP64	LQFP48				floating	wpu	Ext. interrupt	High sink/source	OD	PP		
58	46	-	PD5/TIM1_CH3 /LCD_SEG19(3)/ ADC1_IN9/ COMP1_INP	I/O	FT(5)	**X**	X	X	HS	X	X	**Port D5**	Timer 1 - channel 3 / LCD segment 19 / ADC1_IN9/Comparator 1 positive input
-	-	34	PD5/TIM1_CH3 /LCD_SEG19(3)/ ADC1_IN9/SPI2_MOSI/ COMP1_INP	I/O	FT(5)	**X**	X	X	HS	X	X	**Port D5**	Timer 1 - channel 3 / LCD segment 19 / ADC1_IN9/ SPI2 master out/slave in/Comparator 1 positive input
59	47		PD6/TIM1_BKIN /LCD_SEG20(3)/ ADC1_IN8/RTC_CALIB/ COMP1_INP/VREFINT	I/O	FT(5)	**X**	X	X	HS	X	X	**Port D6**	Timer 1 - break input / LCD segment 20 / ADC1_IN8 / RTC calibration/Comparator 1 positive input/Internal reference voltage output
-	-	35	PD6/TIM1_BKIN /LCD_SEG20(3)/ ADC1_IN8/RTC_CALIB/ SPI2_SCK/COMP1_INP/ VREFINT	I/O	FT(5)	**X**	X	X	HS	X	X	**Port D6**	Timer 1 - break input / LCD segment 20 / ADC1_IN8 / RTC calibration/SPI2 clock/Comparator 1 positive input/Internal reference voltage output
60	48	-	PD7/TIM1_CH1N /LCD_SEG21(3)/ ADC1_IN7/RTC_ALARM/ COMP1_INP/VREFINT	I/O	FT(5)	**X**	X	X	HS	X	X	**Port D7**	Timer 1 - inverted channel 1/ LCD segment 21 / ADC1_IN7 / RTC alarm/Comparator 1 positive input/Internal reference voltage output
-	-	36	PD7/TIM1_CH1N /LCD_SEG21(3)/ ADC1_IN7/RTC_ALARM/ SPI2_NSS/COMP1_INP/V REFINT	I/O	FT(5)	**X**	X	X	HS	X	X	**Port D7**	Timer 1 - inverted channel 1/ LCD segment 21 / ADC1_IN7 / RTC alarm /SPI2 master/slave select/Comparator 1 positive input/Internal reference voltage output
61	49	-	PG4/LCD_SEG32/ SPI2_NSS	I/O	FT(5)	**X**	X	X	HS	X	X	**Port G4**	LCD segment 32 / SPI2 master/slave select
62	50	-	PG5/LCD_SEG33/ SPI2_SCK	I/O	FT(5)	**X**	X	X	HS	X	X	**Port G5**	LCD segment 33 / SPI2 clock
63	51	-	PG6/LCD_SEG34/ SPI2_MOSI	I/O	FT(5)	**X**	X	X	HS	X	X	**Port G6**	LCD segment 34 / SPI2 master out- slave in

Table 5. High-density STM8AL3x8x pin description (continued)

Pin number			Pin name	Type	I/O level	Input			Output			Main function (after reset)	Default alternate function
LQFP80	LQFP64	LQFP48				floating	wpu	Ext. interrupt	High sink/source	OD	PP		
5	1	1	PA0[8]/*[USART1_CK]*[2]/ SWIM/BEEP/IR_TIM [9]	I/O	-	X	**X**	X	HS	X	X	**Port A0**	*[USART1 synchronous clock]*[2] / SWIM input and output / Beep output / Infrared Timer output
68	56	40	V_{SS2}	S	-	**-**	-	-	-	-	-	IOs ground voltage	
67	55	39	V_{DD2}	S	-	**-**	-	-	-	-	-	IOs supply voltage	
48	-	-	V_{SS4}	S	-	**-**	-	-	-	-	-	IOs ground voltage	
47	-	-	V_{DD4}	S	-	**-**	-	-	-	-	-	IOs supply voltage	

1. At power-up, the PA1/NRST pin is a reset input pin with pull-up. To be used as a general purpose pin (PA1), it can be configured only as output open-drain or push-pull, not as a general purpose input. Refer to Section *Configuring NRST/PA1 pin as general purpose output* in STM8L051/L052 Value Line, STM8L151/L152, STM8L162, STM8AL31, STM8AL3L MCU lines reference manual (RM0031).
2. [ ] Alternate function remapping option (if the same alternate function is shown twice, it indicates an exclusive choice not a duplication of the function).
3. Available onSTM8AL3L8xdevices only.
4. A pull-up is applied to PB0 and PB4 during the reset phase. These two pins are input floating after reset release.
5. In the 5 V tolerant I/Os, the protection diode to V_{DD} is not implemented.
6. In the open-drain output column, ‘T’ defines a true open-drain I/O (P-buffer, weak pull-up and protection diode to V_{DD} are not implemented).
7. Available on STM8AL3L8x devices only. On STM8AL318x devices it is reserved and must be tied to V_{DD}.
8. The PA0 pin is in input pull-up during the reset phase and after reset release.
9. High Sink LED driver capability available on PA0.

Note: The slope control of all GPIO pins, except true open drain pins, are programmable. By default the slope control is limited to 2 MHz.

System configuration options

As shown in *Table 5: High-density STM8AL3x8x pin description*, some alternate functions can be remapped on different I/O ports by programming one of the two remapping registers described in the “Routing interface (RI) and system configuration controller” section in STM8L051/L052 Value Line, STM8L151/L152, STM8L162, STM8AL31, STM8AL3L MCU lines reference manual (RM0031).

Table 9. General hardware register map

Address	Block	Register label	Register name	Reset status
0x00 502E to 0x00 5049	Reserved area (44 byte)			
0x00 5050	Flash	FLASH_CR1	Flash control register 1	0x00
0x00 5051		FLASH_CR2	Flash control register 2	0x00
0x00 5052		FLASH _PUKR	Flash program memory unprotection key register	0x00
0x00 5053		FLASH _DUKR	Data EEPROM unprotection key register	0x00
0x00 5054		FLASH _IAPSR	Flash in-application programming status register	0x00
0x00 5055 to 0x00 506F	Reserved area (27 byte)			
0x00 5070	DMA1	DMA1_GCSR	DMA1 global configuration & status register	0xFC
0x00 5071		DMA1_GIR1	DMA1 global interrupt register 1	0x00
0x00 5072 to 0x00 5074	Reserved area (3 byte)			
0x00 5075	DMA1	DMA1_C0CR	DMA1 channel 0 configuration register	0x00
0x00 5076		DMA1_C0SPR	DMA1 channel 0 status & priority register	0x00
0x00 5077		DMA1_C0NDTR	DMA1 number of data to transfer register (channel 0)	0x00
0x00 5078		DMA1_C0PARH	DMA1 peripheral address high register (channel 0)	0x52
0x00 5079		DMA1_C0PARL	DMA1 peripheral address low register (channel 0)	0x00
0x00 507A		Reserved area (1 byte)		
0x00 507B		DMA1_C0M0ARH	DMA1 memory 0 address high register (channel 0)	0x00
0x00 507C		DMA1_C0M0ARL	DMA1 memory 0 address low register (channel 0)	0x00
0x00 507D to 0x00 507E	Reserved area (2 byte)			
0x00 507F	DMA1	DMA1_C1CR	DMA1 channel 1 configuration register	0x00
0x00 5080		DMA1_C1SPR	DMA1 channel 1 status & priority register	0x00
0x00 5081		DMA1_C1NDTR	DMA1 number of data to transfer register (channel 1)	0x00
0x00 5082		DMA1_C1PARH	DMA1 peripheral address high register (channel 1)	0x52
0x00 5083		DMA1_C1PARL	DMA1 peripheral address low register (channel 1)	0x00

Table 9. General hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 5386 to 0x00 5387	Reserved area (2 byte)			
0x00 5388	DAC	DAC_CH1RDHRH	DAC channel 1 right aligned data holding register high	0x00
0x00 5389		DAC_CH1RDHRL	DAC channel 1 right aligned data holding register low	0x00
0x00 538A to 0x00 538B	Reserved area (2 byte)			
0x00 538C	DAC	DAC_CH1LDHRH	DAC channel 1 left aligned data holding register high	0x00
0x00 538D		DAC_CH1LDHRL	DAC channel 1 left aligned data holding register low	0x00
0x00 538E to 0x00 538F	Reserved area (2 byte)			
0x00 5390	DAC	DAC_CH1DHR8	DAC channel 1 8-bit data holding register	0x00
0x00 5391 to 0x00 5393	Reserved area (3 byte)			
0x00 5394	DAC	DAC_CH2RDHRH	DAC channel 2 right aligned data holding register high	0x00
0x00 5395		DAC_CH2RDHRL	DAC channel 2 right aligned data holding register low	0x00
0x00 5396 to 0x00 5397	Reserved area (2 byte)			
0x00 5398	DAC	DAC_CH2LDHRH	DAC channel 2 left aligned data holding register high	0x00
0x00 5399		DAC_CH2LDHRL	DAC channel 2 left aligned data holding register low	0x00
0x00 539A to 0x00 539B	Reserved area (2 byte)			
0x00 539C	DAC	DAC_CH2DHR8	DAC channel 2 8-bit data holding register	0x00
0x00 539D to 0x00 539F	Reserved area (3 byte)			
0x00 53A0	DAC	DAC_DCH1RDHRH	DAC channel 1 right aligned data holding register high	0x00
0x00 53A1		DAC_DCH1RDHRL	DAC channel 1 right aligned data holding register low	0x00
0x00 53A2 to 0x00 53AB	Reserved area (3 byte)			

6 Interrupt vector mapping

Note: Slope control of all GPIO pins can be programmed except true open drain pins and by default is limited to 2 MHz.

Table 11. Interrupt mapping

IRQ No.	Source block	Description	Wakeup from Halt mode	Wakeup from Active-halt mode	Wakeup from Wait (WFI mode)	Wakeup from Wait (WFE mode)(1)	Vector address
	RESET	Reset	Yes	Yes	Yes	Yes	0x00 8000
	TRAP	Software interrupt	-	-	-	-	0x00 8004
0	TLI(2)	External Top level Interrupt	-	-	-	-	0x00 8008
1	FLASH	EOP/WR_PG_DIS	-	-	Yes	Yes(3)	0x00 800C
2	DMA1 0/1	DMA1 channels 0/1	-	-	Yes	Yes(3)	0x00 8010
3	DMA1 2/3	DMA1 channels 2/3	-	-	Yes	Yes(3)	0x00 8014
4	RTC/LSE_ CSS	RTC alarm interrupt/LSE CSS interrupt	Yes	Yes	Yes	Yes	0x00 8018
5	EXTI E/F/PVD(4)	PortE/F interrupt/PVD interrupt	Yes	Yes	Yes	Yes(3)	0x00 801C
6	EXTIB/G	External interrupt port B/G	Yes	Yes	Yes	Yes(3)	0x00 8020
7	EXTID/H	External interrupt port D/H	Yes	Yes	Yes	Yes(3)	0x00 8024
8	EXTI0	External interrupt 0	Yes	Yes	Yes	Yes(3)	0x00 8028
9	EXTI1	External interrupt 1	Yes	Yes	Yes	Yes(3)	0x00 802C
10	EXTI2	External interrupt 2	Yes	Yes	Yes	Yes(3)	0x00 8030
11	EXTI3	External interrupt 3	Yes	Yes	Yes	Yes(3)	0x00 8034
12	EXTI4	External interrupt 4	Yes	Yes	Yes	Yes(3)	0x00 8038
13	EXTI5	External interrupt 5	Yes	Yes	Yes	Yes(3)	0x00 803C
14	EXTI6	External interrupt 6	Yes	Yes	Yes	Yes(3)	0x00 8040
15	EXTI7	External interrupt 7	Yes	Yes	Yes	Yes(3)	0x00 8044
16	LCD	LCD interrupt	-	-	Yes	Yes	0x00 8048
17	CLK/ TIM1/ DAC	System clock switch/CSS interrupt/TIM1 break/DAC	-	-	Yes	Yes	0x00 804C
18	COMP1/ COMP2 ADC1	Comparator 1 and 2 interrupt/ADC1	Yes	Yes	Yes	Yes(3)	0x00 8050

Table 11. Interrupt mapping (continued)

IRQ No.	Source block	Description	Wakeup from Halt mode	Wakeup from Active-halt mode	Wakeup from Wait (WFI mode)	Wakeup from Wait (WFE mode)(1)	Vector address
19	TIM2/ USART2	TIM2 update /overflow/trigger/break/ USART2 transmission complete/transmit data register empty interrupt	-	-	Yes	Yes(3)	0x00 8054
20	TIM2/ USART2	Capture/Compare/USART 2 interrupt	-	-	Yes	Yes(3)	0x00 8058
21	TIM3/ USART3	TIM3 Update /Overflow/Trigger/Break/ USART3 transmission complete/transmit data register empty interrupt	-	-	Yes	Yes(3)	0x00 805C
22	TIM3/ USART3	TIM3 Capture/Compare/ USART3 Receive register data full/overrun/idle line detected/parity error/ interrupt	-	-	Yes	Yes(3)	0x00 8060
23	TIM1	Update /overflow/trigger/ COM	-	-	-	Yes(3)	0x00 8064
24	TIM1	Capture/Compare	-	-	-	Yes(3)	0x00 8068
25	TIM4	Update/overflow/trigger	-	-	Yes	Yes(3)	0x00 806C
26	SPI1	End of Transfer	Yes	Yes	Yes	Yes(3)	0x00 8070
27	USART 1/ TIM5	USART1 transmission complete/transmit data register empty/ TIM5 update/overflow/ trigger/break	-	-	Yes	Yes(3)	0x00 8074
28	USART 1/ TIM5	USART1 Receive register data full/overrun/idle line detected/parity error/ TIM5 capture/compare	-	-	Yes	Yes(3)	0x00 8078
29	I^2C1/SPI2	I^2C1 interrupt(5)/ SPI2	Yes	Yes	Yes	Yes(3)	0x00 807C

1. The Low-power wait mode is entered when executing a WFE instruction in Low-power run mode.
2. The TLI interrupt is the logic OR between TIM2 overflow interrupt, and TIM4 overflow interrupts.
3. In WFE mode, this interrupt is served if it has been previously enabled. After processing the interrupt, the processor goes back to WFE mode. When this interrupt is configured as a wakeup event, the CPU wakes up and resumes processing.
4. The interrupt from PVD is logically OR-ed with Port E and F interrupts. Register EXTI_CONF allows to select between Port E and Port F interrupt. See more details about the external interrupt port select register (EXTI_CONF) in the STM8L051/L052 Value Line, STM8L151/L152, STM8L162, STM8AL31, STM8AL3L MCU lines reference manual (RM0031).
5. The device is woken up from Halt or Active-halt mode only when the address received matches the interface address.

9 Electrical parameters

9.1 Parameter conditions

Unless otherwise specified, all voltages are referred to V_{SS}.

9.1.1 Minimum and maximum values

Unless otherwise specified the minimum and maximum values are guaranteed in the worst conditions of ambient temperature, supply voltage and frequencies by tests in production on 100% of the devices with an ambient temperature at T_A= 25 °C and T_A = T_A max (given by the selected temperature range).

Data based on characterization results, design simulation and/or technology characteristics are indicated in the table footnotes and are not tested in production.

9.1.2 Typical values

Unless otherwise specified, typical data are based on T_A = 25 °C, V_{DD} = 3 V. They are given only as design guidelines and are not tested.

Typical ADC and DAC accuracy values are determined by characterization of a batch of samples from a standard diffusion lot over the full temperature range.

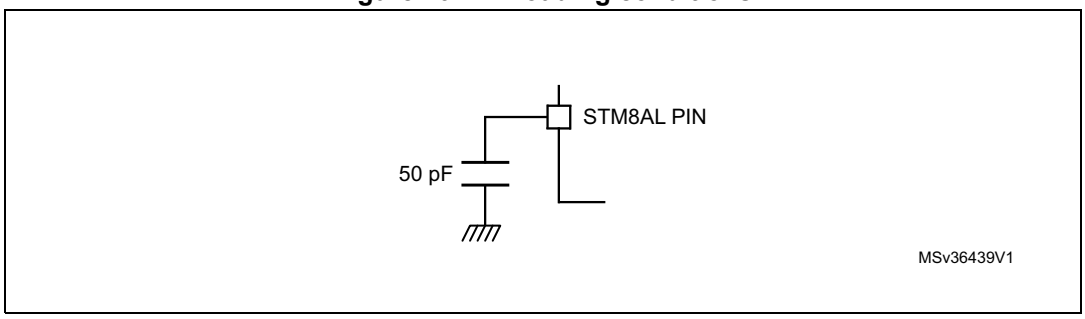
9.1.3 Typical curves

Unless otherwise specified, all typical curves are given only as design guidelines and are not tested.

9.1.4 Loading capacitor

The loading conditions used for pin parameter measurement are shown in *Figure 10*.

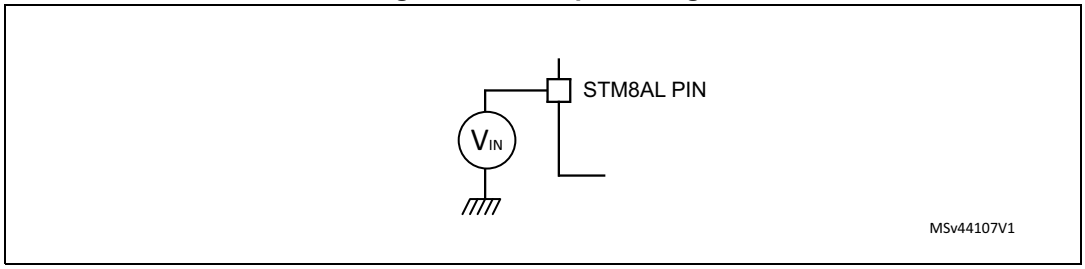
Figure 10. Pin loading conditions



9.1.5 Pin input voltage

The input voltage measurement on a pin of the device is described in *Figure 11*.

Figure 11. Pin input voltage



9.2 Absolute maximum ratings

Stresses above the absolute maximum ratings listed in *Table 15: Voltage characteristics*, *Table 16: Current characteristics* and *Table 17: Thermal characteristics* may cause permanent damage to the device. These are stress ratings only, and a functional operation of the device at these conditions is not implied. Exposure to maximum rating conditions for extended periods of time may affect the device's reliability.

The device's mission profile (application conditions) is compliant with the JEDEC JESD47 qualification standard, its extended mission profiles are available on demand.

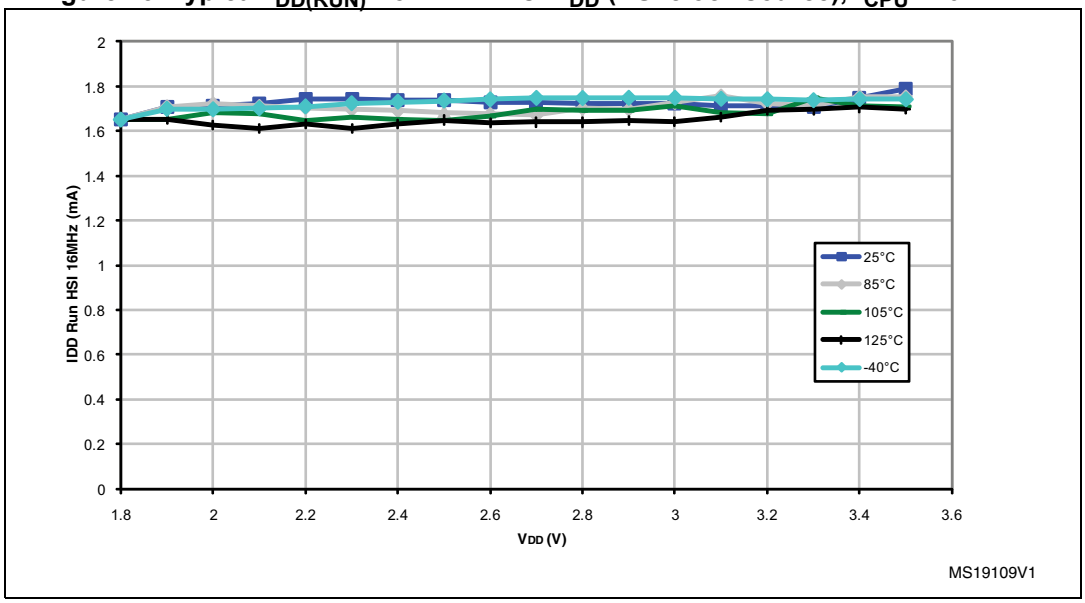
Table 15. Voltage characteristics

Symbol	Ratings	Min	Max	Unit
V_{DD}- V_{SS}	External supply voltage (including V_{DDA})(1)	- 0.3	4.0	V
V_{IN}(2)	Input voltage on true open-drain pins (PC0 and PC1)	V_{SS} - 0.3	V_{DD} + 4.0	
	Input voltage on five-volt tolerant (FT) pins		V_{DD} + 4.0	
	Input voltage on any other pin		4.0	
V_{ESD}	Electrostatic discharge voltage	see *Absolute maximum ratings (electrical sensitivity) on page 116*		

1. All power (V_{DD1}, V_{DD2}, V_{DD3}, V_{DD4}, V_{DDA}) and ground (V_{SS1}, V_{SS2}, V_{SS3}, V_{SS4}, V_{SSA}) pins must always be connected to the external power supply.
2. V_{IN} maximum must always be respected. Refer to *Table 16.* for maximum allowed injected current values.

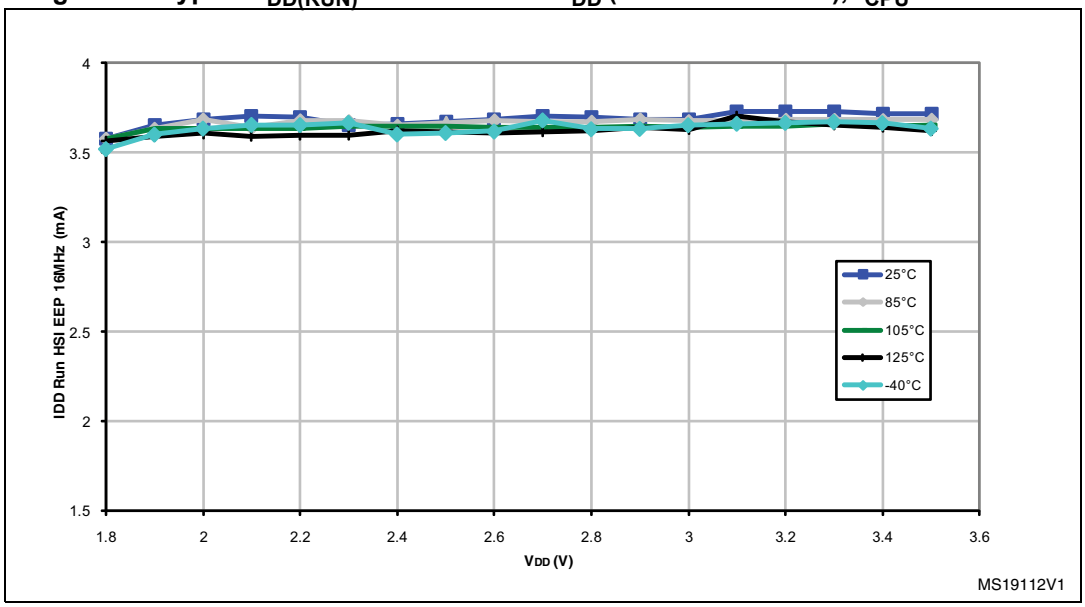
1. CPU executing typical data processing
2. The run from RAM consumption is approximated with the linear formula:
   I_{DD}(run_from_RAM) = Freq. * 95 µA/MHz + 250 µA
3. Guaranteed by characterization results.
4. Oscillator bypassed (HSEBYP = 1 in CLK_ECKCR). When configured for external crystal, the HSE consumption ($I_{DD\ HSE}$) must be added. Refer to *Table 32*.
5. The run from Flash consumption is approximated with the linear formula:
   I_{DD}(run_from_Flash) = Freq. * 200 µA/MHz + 330 µA
6. Oscillator bypassed (LSEBYP = 1 in CLK_ECKCR). When configured for external crystal, the LSE consumption ($I_{DD\ LSE}$) must be added. Refer to *Table 33*

Figure 13. Typical $I_{DD(RUN)}$ from RAM vs. V_{DD} (HSI clock source), f_{CPU} =16 MHz(1)



1. Typical current consumption measured with code executed from RAM.

Figure 14. Typical $I_{DD(RUN)}$ from Flash vs. V_{DD} (HSI clock source), f_{CPU} = 16 MHz(1)



1. Typical current consumption measured with code executed from Flash.

Low speed internal RC oscillator (LSI)

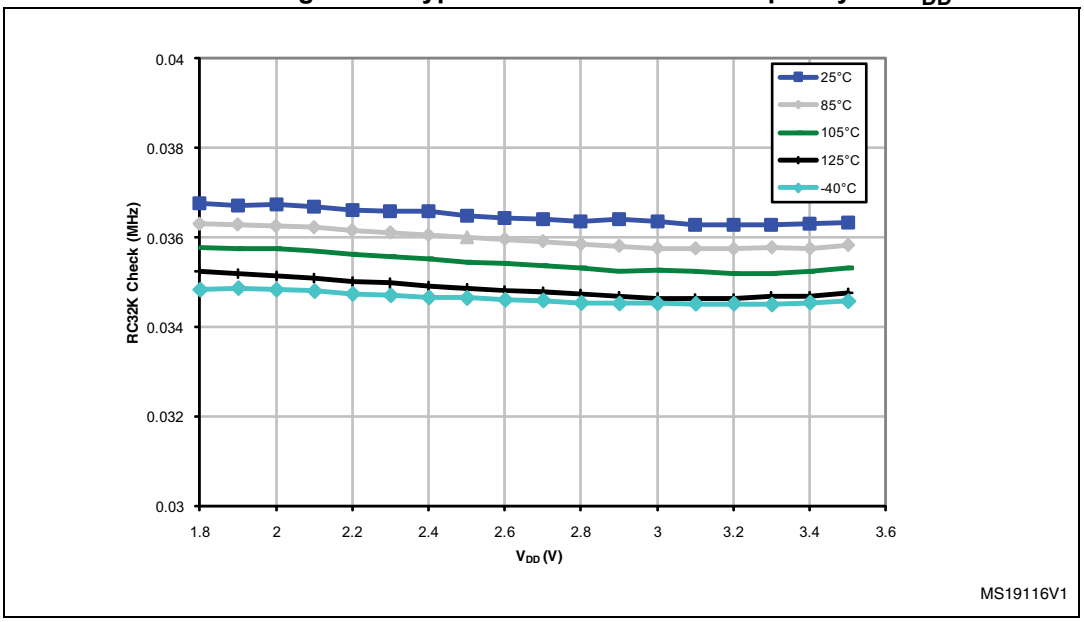
In the following table, data are based on characterization results, not tested in production, unless otherwise specified.

Table 35. LSI oscillator characteristics

Symbol	Parameter	Conditions(1)	Min.	Typ.	Max.	Unit
f_{LSI}	Frequency	-	26	38	56	kHz
$t_{su(LSI)}$	LSI oscillator wakeup time	-	-	-	200(2)	µs
$D_{(LSI)}$	LSI oscillator frequency drift(3)	0 °C ≤T_A ≤85 °C	-12	-	11	%

1. V_{DD} = 1.65 V to 3.6 V, T_A = -40 to 125 °C unless otherwise specified.
2. Guaranteed by design.
3. This is a deviation for an individual part, once the initial frequency has been measured.

Figure 24. Typical LSI clock source frequency vs. V_{DD}



9.3.5 Memory characteristics

T_A = -40 to 125 °C unless otherwise specified.

Table 36. RAM and hardware registers

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
V_{RM}	Data retention mode (1)	Halt mode (or Reset)	1.65	-	-	V

1. Minimum supply voltage without losing data stored in RAM (in Halt mode or under Reset) or in hardware registers (only in Halt mode). Guaranteed by characterization results.

Figure 27. Typical pull-up resistance R_{PU} vs. V_{DD} with $V_{IN}=V_{SS}$

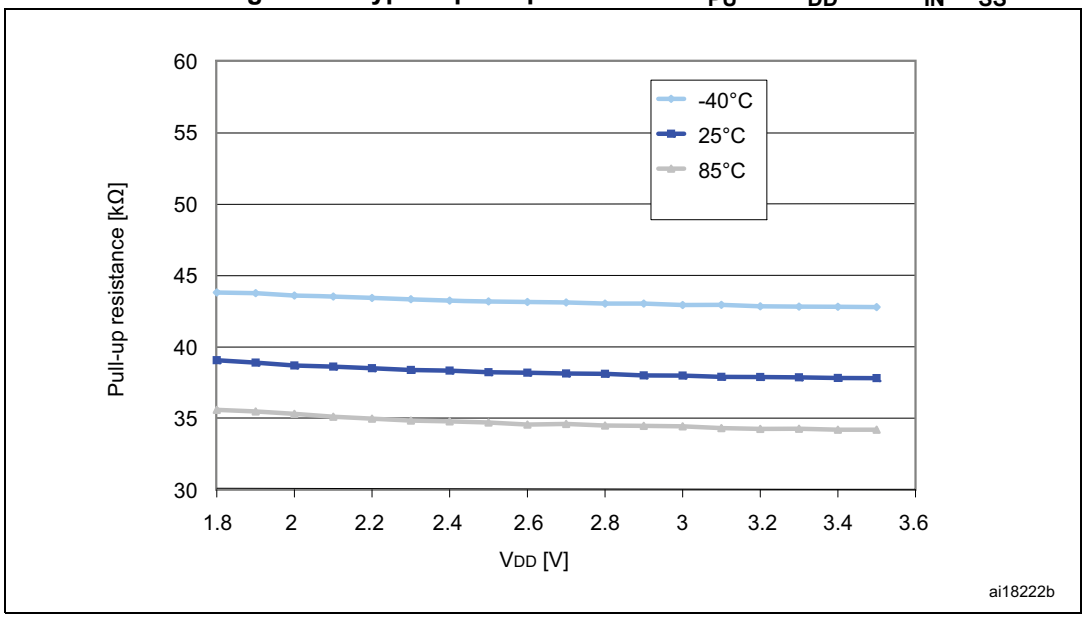
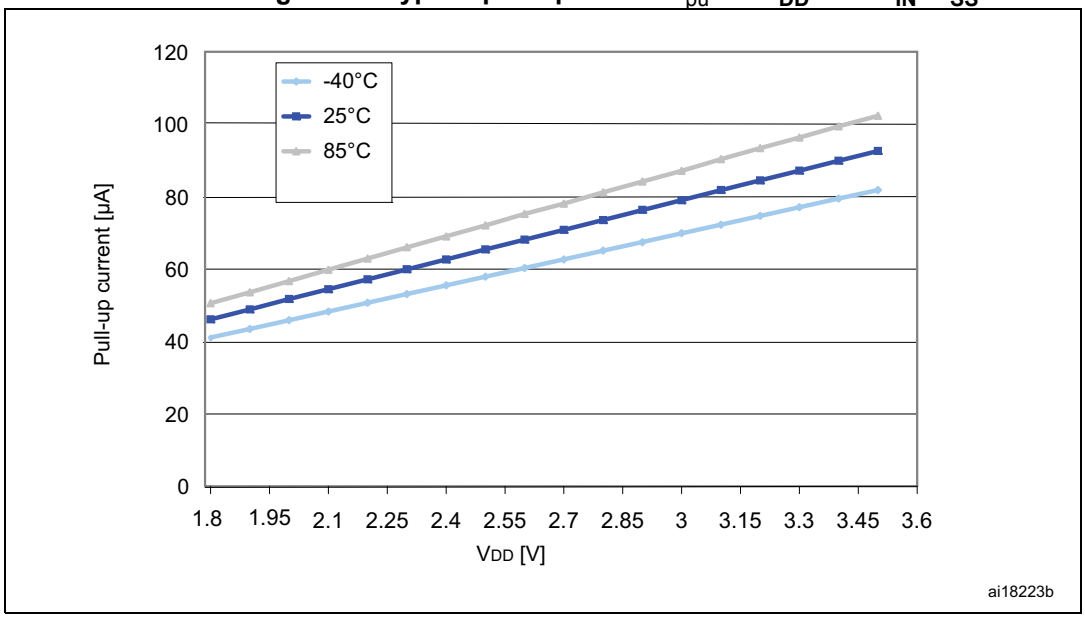


Figure 28. Typical pull-up current I_{pu} vs. V_{DD} with $V_{IN}=V_{SS}$



Output driving current

Subject to general operating conditions for V_{DD} and T_A unless otherwise specified.

NRST pin

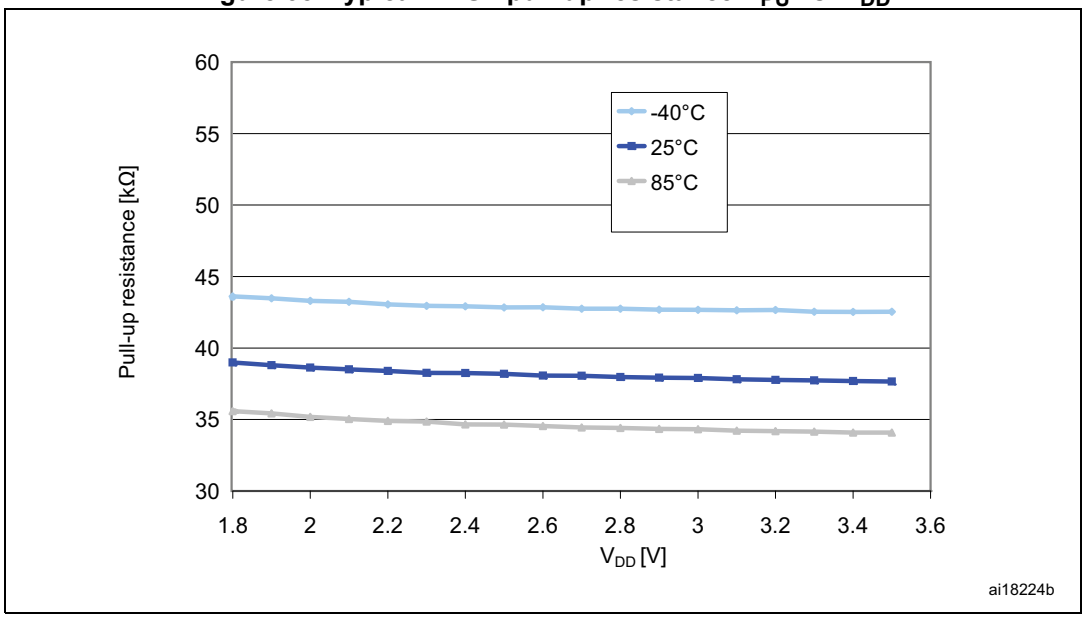
Subject to general operating conditions for V_{DD} and T_A unless otherwise specified.

Table 45. $\overline{\text{NRST}}$ pin characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$V_{IL(NRST)}$	NRST input low-level voltage	-	V_{SS}(1)	-	0.8(1)	V
$V_{IH(NRST)}$	NRST input high-level voltage (1)	-	1.4(1)	-	V_{DD}(1)	
$V_{OL(NRST)}$	NRST output low-level voltage (1)	I_{OL} = 2 mA for 2.7 V ≤V_{DD} ≤3.6 V	-	-	0.4(1)	
		I_{OL} = 1.5 mA for V_{DD} < 2.7 V	-	-		
V_{HYST}	NRST input hysteresis	-	10%V_{DD} (2)(3)	-	-	mV
$R_{PU(NRST)}$	NRST pull-up equivalent resistor	-	30(1)	45	60(1)	kΩ
$V_{F(NRST)}$	NRST input filtered pulse	-	-	-	50(3)	ns
$V_{NF(NRST)}$	NRST input not filtered pulse	-	300(3)	-	-	

1. Guaranteed by characterization results.
2. 200 mV min.
3. Guaranteed by design.

Figure 35. Typical NRST pull-up resistance R_{PU} vs. V_{DD}



9.3.9 LCD controller (STM8AL3L8x only)

In the following table, data are guaranteed by design, not tested in production.

Table 48. LCD characteristics

Symbol	Parameter	Min.	Typ.	Max.	Unit
V_{LCD}	LCD external voltage	-	-	3.6	V
V_{LCD0}	LCD internal reference voltage 0	-	2.6	-	
V_{LCD1}	LCD internal reference voltage 1	-	2.7	-	
V_{LCD2}	LCD internal reference voltage 2	-	2.8	-	
V_{LCD3}	LCD internal reference voltage 3	-	3.0	-	
V_{LCD4}	LCD internal reference voltage 4	-	3.1	-	
V_{LCD5}	LCD internal reference voltage 5	-	3.2	-	
V_{LCD6}	LCD internal reference voltage 6	-	3.4	-	
V_{LCD7}	LCD internal reference voltage 7	-	3.5	-	
C_{EXT}	V_{LCD} external capacitance	0.1	1	2	µF
I_{DD}	Supply current(1) at V_{DD} = 1.8 V	-	3	-	µA
	Supply current(1) at V_{DD} = 3 V	-	3	-	
R_{HN}(2)	High value resistive network (low drive)	-	6.6	-	MΩ
R_{LN}(3)	Low value resistive network (high drive)	-	240	-	kΩ
V_{33}	Segment/Common higher level voltage	-	-	V_{LCDx}	V
V_{34}	Segment/Common 3/4 level voltage	-	$3/4V_{LCDx}$	-	
V_{23}	Segment/Common 2/3 level voltage	-	$2/3V_{LCDx}$	-	
V_{12}	Segment/Common 1/2 level voltage	-	$1/2V_{LCDx}$	-	
V_{13}	Segment/Common 1/3 level voltage	-	$1/3V_{LCDx}$	-	
V_{14}	Segment/Common 1/4 level voltage	-	$1/4V_{LCDx}$	-	
V_0	Segment/Common lowest level voltage	0	-	-	

1. LCD enabled with 3 V internal booster (LCD_CR1 = 0x08), 1/4 duty, 1/3 bias, division ratio= 64, all pixels active, no LCD connected.
2. R_{HN} is the total high value resistive network.
3. R_{LN} is the total low value resistive network.

VLCD external capacitor (STM8AL3L8x only)

The application achieves a stabilized LCD reference voltage when connecting an external capacitor C_{EXT} to the V_{LCD} pin. C_{EXT} is specified in *Table 48*.

9.3.13 12-bit DAC characteristics

In the following table, data are guaranteed by design, not tested in production.

Table 53. DAC characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
V_{DDA}	Analog supply voltage	-	1.8	-	3.6	V
V_{REF+}	Reference supply voltage	-	1.8	-	V_{DDA}	
I_{VREF}	Current consumption on V_{REF+} supply	V_{REF+} = 3.3 V, no load, middle code (0x800)	-	130	220	µA
		V_{REF+} = 3.3 V, no load, worst code (0x000)	-	220	350	
I_{VDDA}	Current consumption on V_{DDA} supply	V_{DDA} = 3.3 V, no load, middle code (0x800)	-	210	320	
		V_{DDA} = 3.3 V, no load, worst code (0x000)	-	320	520	
T_A	Temperature range	-	-40	-	125	°C
R_L (1) (2)	Resistive load	DACOUT buffer ON	5	-		kΩ
R_O	Output impedance	DACOUT buffer OFF	-	8	10	kΩ
C_L (3)	Capacitive load	-	-	-	50	pF
DAC_OUT (4)	DAC_OUT voltage	DACOUT buffer ON	0.2	-	V_{DDA} - 0.2	V
		DACOUT buffer OFF	0	-	V_{REF+} -1 LSB	V
$t_{settling}$	Settling time (full scale: for a 12-bit input code transition between the lowest and the highest input codes when DAC_OUT reaches the final value ±1LSB)	R_L ≥5 kΩ, C_L≤ 50 pF	-	7	12	µs
Update rate	Max frequency for a correct DAC_OUT (@95%) change when small variation of the input code (from code i to i+1LSB).	R_L ≥ 5 kΩ, C_L ≤50 pF	-	-	1	Msps
t_{WAKEUP}	Wakeup time from OFF state. Input code between lowest and highest possible codes.	R_L ≥5 kΩ, C_L≤50 pF	-	9	15	µs
PSRR+	Power supply rejection ratio (to V_{DDA}) (static DC measurement)	R_L≥ 5 kΩ, C_L≤50 pF	-	-60	-35	dB

1. Resistive load between DACOUT and GNDA
2. Output on PF0 or PF1
3. Capacitive load at DACOUT pin
4. It gives the output excursion of the DAC

Table 59. ADC1 accuracy with $V_{DDA} = V_{REF}^{+} = 1.8$ V to 2.4 V (continued)

Symbol	Parameter	Typ.	Max.(1)	Unit
Offset	Offset error	2	3	LSB
Gain	Gain error	2	3	LSB

1. Guaranteed by characterization results.

Figure 42. ADC1 accuracy characteristics

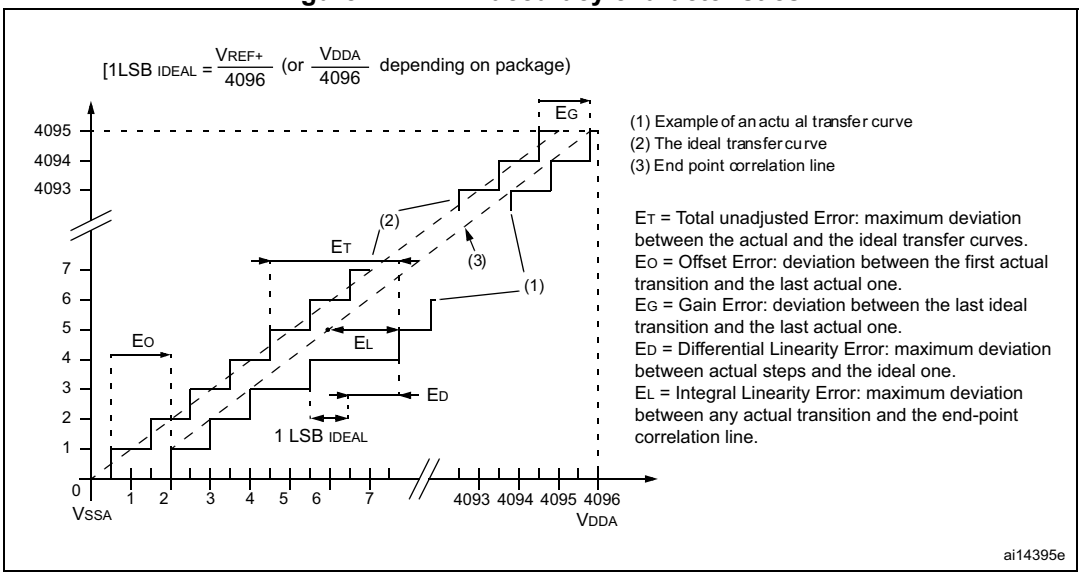
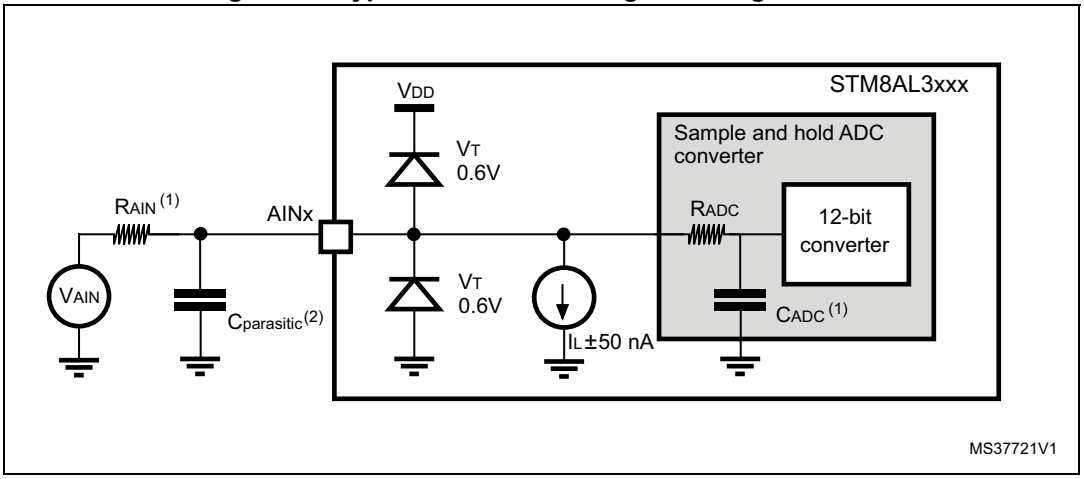


Figure 43. Typical connection diagram using the ADC



1. Refer to *Table 56* for the values of R_{AIN} and C_{ADC}.
2. $C_{parasitic}$ represents the capacitance of the PCB (dependent on soldering and PCB layout quality) plus the pad capacitance (roughly 7 pF). A high $C_{parasitic}$ value will downgrade conversion accuracy. To remedy this, f_{ADC} should be reduced.

General PCB design guidelines

Power supply decoupling should be performed as shown in *Figure 44* or *Figure 45*, depending on whether V_{REF+} is connected to V_{DDA} or not. Good quality ceramic 10 nF capacitors should be used. They should be placed as close as possible to the chip.